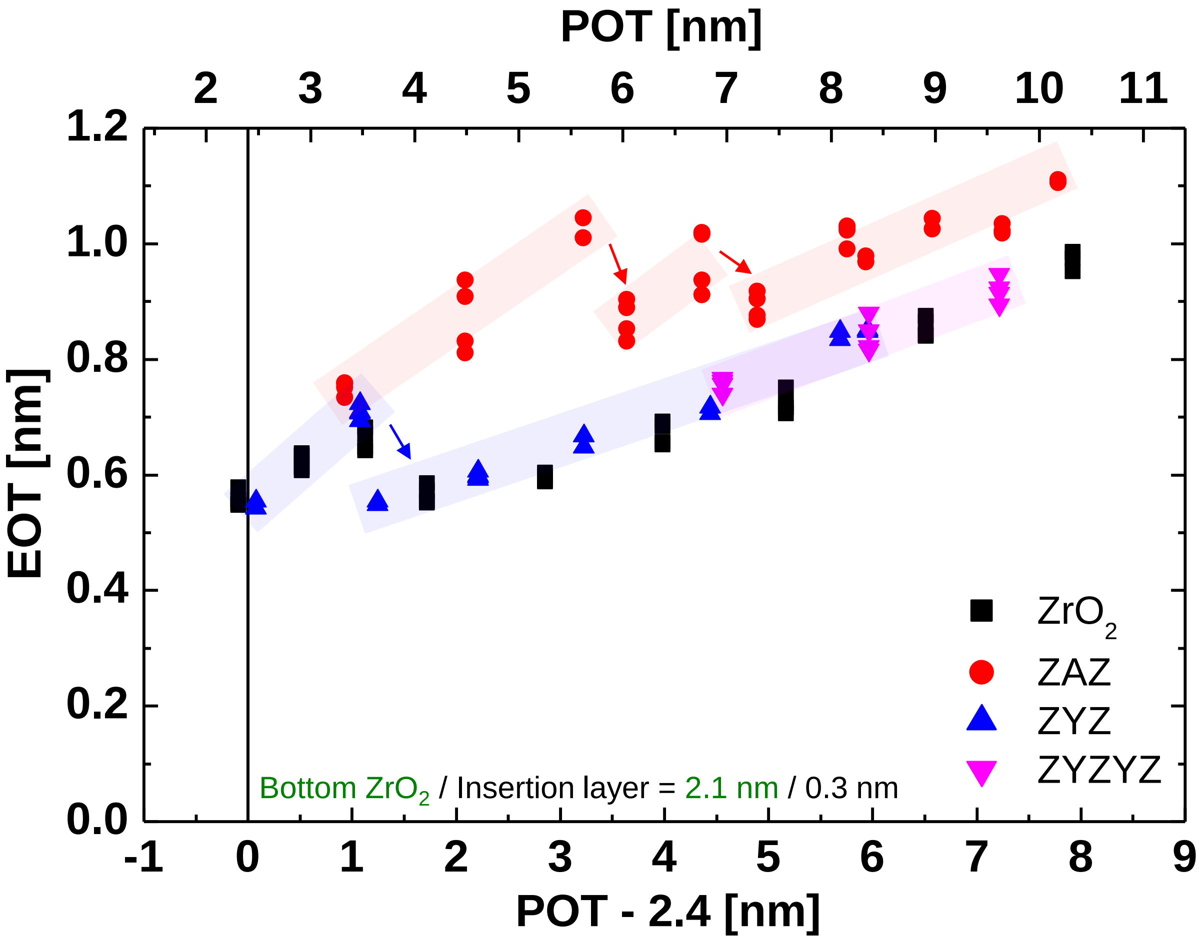

Figure 1 EOT – POT curves of each dielectric material (undoped ZrO_2, ZAZ, ZYZ, and ZYZYZ) based MIM capacitors. The thickness of the top ZrO_2 layer (denoted as "POT minus 2.4") was also demonstrated in order to calculate the y-intercept of each slope, which implies the effective EOT of the [bottom ZrO_2 (~ 2.1 nm) / insertion layer (~ 0.3 nm)] in the case of ZAZ and ZYZ films.